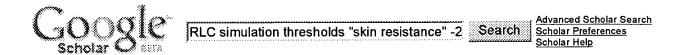
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5	BRS	L8	1	((high adj frequency) same simulation) and (circuit adj design) and (skin adj resistance)	US- PGPUB	2006/01/26 16:19
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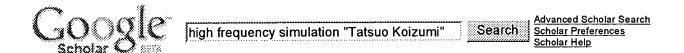


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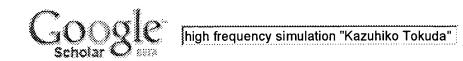


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> Fisher, R.; Shiraki, Y.; Tokuda, K.; Hamaguchi, K.; Shoji, Y.; Ogawa, H.; Wireless Communication Technology, 2003. IEEE Topical Conference on 15-17 Oct. 2003 Page(s):310 - 311

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3	BRS	L3	1036	(circuits same (high adj frequency)) and (threshold\$)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:15
4	BRS	L4	1		USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:15
5	BRS	L5	1	(simulation and (high adj frequency)) and (circuits same (high adj frequency)) and (thresholds) and (skin near resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:16
6	BRS	L6	40	(simulation same substrates) and (thresholds same integration)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:18
7	BRS	L7	40	(simulation same substrates) and (thresholds same integration)	USPAT; EPO; JPO DERWEN T; IBM_TDB	2006/01/26 10:18
8	BRS	L8	4	(simulation same substrates) and (thresholds same integration) and (high adj frequency)	USPAT; EPO; JPO DERWEN T; IBM_TDB	; 2006/01/26 10:18

<u> </u>	Туре	L#	Hits	Search Text	DBs	Time Stamp
9	BRS	L9	1	(simulation same substrates) and (thresholds same integration) and (high adj frequency) and wires\$	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:18
10	BRS	L10	2	(simulation same substrates) and (thresholds same integration) and (high adj frequency) and wire\$		2006/01/26 10:19
11	BRS	L11	1	(simulation same substrates) and (thresholds same integration) and (high adj frequency) and wire\$ and skin	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:22
12	BRS	L12	2	"6925430".pn.	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:26
13	BRS	L14	o	(substrate and (simulation or model) and (high adj frequency)).ti.	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:26
14	BRS	L13	224		USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:28
15	BRS	L15	100	(substrate and (simulation)).ti.	USPAT; EPO; JPO DERWEN T; IBM_TDB	2006/01/26 10:28
16	BRS	L16	0	(substrate and (simulation)).ti. and substrate and simulation and cicuits and wires and skin	USPAT; EPO; JPO DERWEN T; IBM_TDB	, 2006/01/26 10:28

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17	BRS	L17	4	(substrate and (simulation)).ti. and substrate and simulation and circuits and wires	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:29
18	BRS	L18	0	(substrate and (simulation)).ti. and substrate and simulation and circuits and wires and resitance	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:29
19	BRS	L19	0	(substrate and (simulation)).ti. and substrate and simulation and circuits and threshold	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:29
20	BRS	L20	18	(substrate and (simulation)).ti. and substrate and simulation and circuits	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:31
21	BRS	L21	1	(simulation same (wiring near pattern)) and thresholds and (high adj frequency)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:32
22	BRS	L22	560	(first adj threshold) and (second adj threshold) and wiring and circuits	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:40
23	BRS	L23	0	(first adj threshold) and (second adj threshold) and wiring and circuits and (resitance same calculation)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:40
24	BRS	L24	0	(first adj threshold) and (second adj threshold) and wiring and circuits and (resitance near calculation)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:40

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26	BRS	L26	0	(first adj threshold) and (second adj threshold) and wiring and circuits and slomg	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:40
27	BRS	L27	11	(first adj threshold) and (second adj threshold) and wiring and circuits and skin	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:41
28	BRS	L28	0	(first adj threshold) and (second adj threshold) and wiring and (skin adj resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
29	BRS	L29	0	(first adj threshold) and (second adj threshold) and wiring and (skin near resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
30	BRS	L30	308	(first adj threshold) and (second adj threshold) and wiring and (resistance\$)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
31	BRS	L31	0	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and calulation	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
32	BRS	L32	173	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and substrates	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:43

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33	BRS	L33	173	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and substrates	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:43
34	BRS	L34	173	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and substrates	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:44
35	BRS	L35	0	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and elementsa	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:44
36	BRS	L36	249	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and elements	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:44
37	BRS	L37	8	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and (elements near plurality)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:00
38	BRS	L38	0	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and (elements near plurality) and (high adj frequency)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:47
39	BRS	L39	15	(first adj threshold) and (second adj threshold) and wiring and (resistance\$ same calcu\$)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:01
40	BRS	L40	4	(first adj threshold) and (second adj threshold) and wiring and (resistance\$ same calcu\$) and simulation	USPAT; EPO; JPO; DERWEN T; IBM_TDB	

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42	BRS	L42	4	746/5 cale and (first adi throubold) and	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:14
43	BRS	L43	2	716/5.ccls. and (first adj threshold) and (second adj threshold) and resistance	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:15
44	BRS	L44	0	716/5.ccls. and (DC adj resitance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:15
45	BRS	L45	0	716/5.ccls. and (skin adj resitance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:16
46	BRS	L46	11	716/5.ccls. and ((move or sort or arrange) same resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:16

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